

(19) World Intellectual Property Organization
International Bureau



(43) International Publication Date
7 December 2000 (07.12.2000)

PCT

(10) International Publication Number
WO 00/74108 A2

(51) International Patent Classification⁷: **H01L**

(21) International Application Number: PCT/SG99/00048

(22) International Filing Date: 28 May 1999 (28.05.1999)

(25) Filing Language: English

(26) Publication Language: English

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(81) Designated States (*national*): AE, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, CA, CH, CN, CU, CZ, DE, DK, EE, ES, FI, GB, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MD, MG, MK, MN, MW, MX, NO, NZ, PL, PT, RO, RU, SD, SE, SG, SI, SK, SL, TJ, TM, TR, TT, UA, UG, US, UZ, VN, YU, ZA, ZW.

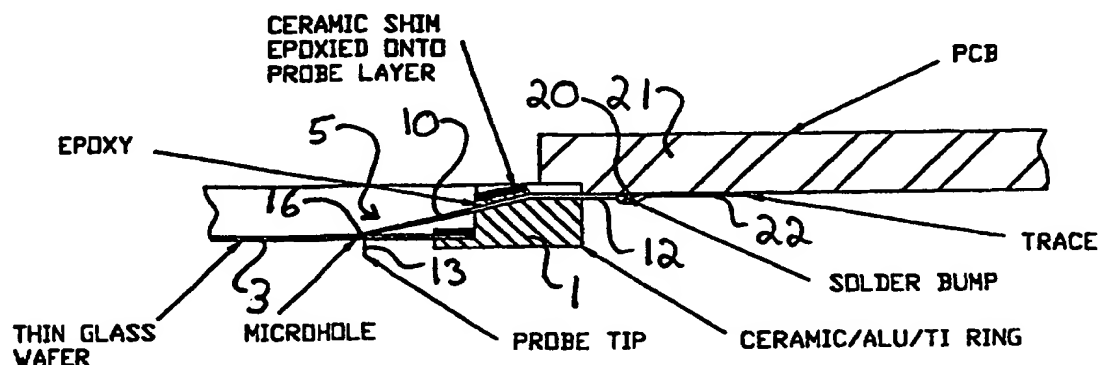
(84) Designated States (*regional*): ARIPO patent (GH, GM, KE, LS, MW, SD, SL, SZ, UG, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GW, ML, MR, NE, SN, TD, TG).

Published:

— Without international search report and to be republished upon receipt of that report.

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

(54) Title: AN INTERFACE DEVICE



(57) Abstract: An interface device (2) provides an interface between testing equipment and an integrated circuit to be tested. The interface device (2) includes a body member (7). A number of elongate contact members (5) are mounted on the body member (7). Each contact member (5) includes a contact end (10), adapted to contact a bond pad of the integrated circuit to be tested, and a body portion (11). The interface device also includes a guide member mounted on the body member (7). The guide member includes a substantially planar member having a number of apertures therein, and the contact end of each elongate member extending through a respective aperture in the guide member.

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